L Number	Hits	Search Text	DB	Time stamp
-	1	"878554"	US-PGPUB	2003/12/25 08:43
	11	714/741.ccis.	us-PGPUB	2003/12/24
-	125	714/741.ccis.	USPAT; US-PGPUB	2003/12/24
-	13	714/741.ccls. and good with simulation	USPAT; US-PGPUB	2003/12/24
-	38	714/741.ccls. and (good reference) with simulation	USPAT; US-PGPUB	2003/12/25
-	40	714/741.ccls. and (good reference gold golden) with (simulation simulate simulates simulated simulating)	USPAT; US-PGPUB	2003/12/25 07:49
-	12	714/741.ccls. and (good reference gold golden) with (simulation simulate simulates simulated simulating) and ((fault defect) adj simulation)	USPAT; US-PGPUB	2003/12/25 07:52
-	12	714/741.ccls. and (good reference gold golden) with (simulation simulate simulates simulated simulating simulator) and ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 07:56
	12	714/741.ccls. and ((logic circuit) adj (simulation simulator)) and ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 07:57
-	12	714/741.ccls. and ((logic circuit logical) adj (simulation simulator)) and ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 08:31
-	623	714/741.ccls. ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 08:20
-	33	714/741.ccls. and ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 08:21
-	5	(714/741.ccls. and ((logic circuit logical) adj (simulation simulator)) and ((fault defect) adj (simulation simulator))) not (714/741.ccls. and (good reference gold golden) with (simulation simulate simulates simulated simulating simulator) and ((fault defect) adj (simulation simulator)))	USPAT; US-PGPUB	2003/12/25 08:21
-	14	714/741.ccls. and ((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 08:35
-	13	714/741.ccls. and ((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults)	USPAT; US-PGPUB	2003/12/25 08:35
-	13	714/741.ccls. and ((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults)	USPAT; US-PGPUB	2003/12/25 08:35
-	14	714/741.ccls. and ((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects)	USPAT; US-PGPUB	2003/12/25 08:47
-	1	"878554" and value with node	US-PGPUB	2003/12/25 08:44
-	7	714/741.ccls. and ((I gic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulat r)) and (fault faults defect defects) and (node n des)	USPAT; US-PGPUB	2003/12/25 08:51

-	94	(((logic circuit gical (fault adj free)) adj (simulati n simulat r)) and ((fault defect) adj	USPAT; US-PGPUB	2003/12/25 08:52
		(simulation simulator)) and (fault faults defect		
		defects) and (node n des)) not (714/741.ccls.		
		and ((I gic circuit logical (fault adj free)) adj		
		(simulati n simulator)) and ((fault defect) adj		
		(simulation simulat r)) and (fault faults defect		
		defects) and (node nodes))		
-	101	((logic circuit logical (fault adj free)) adj	USPAT;	2003/12/25
		(simulation simulator)) and ((fault defect) adj	US-PGPUB	09:06
		(simulation simulator)) and (fault faults defect		
	104	defects) and (node nodes)	HCDAT.	2003/12/25
-	106	((logic circuit logical (fault adj free)) adj	USPAT;	09:17
		(simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults defect	US-PGPUB; EPO; JPO;	07:17
	İ	defects) and (node nodes)	DERWENT;	
		defects) and (node nodes)	IBM TDB	
_	96	((logic circuit logical (fault adj free)) adj	USPAT;	2003/12/25
	78	(logic circuit logical (lault auf liee)) auf (simulation simulator)) and ((fault defect) adj	US-PGPUB;	11:43
		(simulation simulator)) and (fault defect) adj	EPO; JPO;	
		defects) and (node nodes) and ((test adj vector)	DERWENT;	
		pattern)	IBM TDB	
-	10	(((logic circuit logical (fault adj free)) adj	USPAT;	2003/12/25
		(simulation simulator)) and ((fault defect) adj	US-PGPUB;	09:19
		(simulation simulator)) and (fault faults defect	EPO; JPO;	
		defects) and (node nodes)) not (((logic circuit	DERWENT;	
		logical (fault adj free)) adj (simulation simulator))	IBM TDB	
		and ((fault defect) adj (simulation simulator)) and	_	
		(fault faults defect defects) and (node nodes) and		
		((test adj vector) pattern))	,	
-	12	((logic circuit logical (fault adj free)) adj	USPAT;	2003/12/25
		(simulation simulator)) and ((fault defect) adj	us-PGPUB;	09:57
		(simulation simulator)) and (fault faults defect	EPO; JPO;	
		defects) and (node nodes) and ((test adj vector)	DERWENT;	
		pattern) and (backtracing backtrace backtraced	IBM_TDB	
		backtraces (back near (trace traces traced		
_	4 .	tracing))) ((logic circuit logical (fault adi fron)) adi	USPAT:	2003/12/25
-	15	((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj	US-PGPUB;	10:01
		(simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults defect	EPO; JPO;	10.01
		defects) and (node nodes) and ((test adj vector)	DERWENT;	
		pattern) and (backtracing backtrace backtraced	IBM TDB	
		backtraces backwardtrace backwardtraces	1017_100	
		backwardtraced backwardtracing ((back backward)		
		near (trace traces traced tracing)))		
	15	((logic circuit logical (fault adj free)) adj	USPAT;	2003/12/25
		(simulation simulator)) and ((fault defect) adj	US-PGPUB;	10:43
		(simulation simulator)) and (fault faults defect	EPO; JPO;	
		defects) and (node nodes) and ((test adj vector)	DERWENT;	
		pattern) and (backtracing backtrace backtraced	IBM_TDB	
		backtraces backwardtrace backwardtraces		
		backwardtraced backwardtracing ((back backward)		
		near (trace traces traced tracing drive)))		

-	22	((I gic circuit logical (fault adj free)) adj (simulati n simulat r)) and ((fault defect) adj (simulati n simulator)) and (fault faults defect defects) and (node nodes) and ((test adj vector) pattern) and (backtracing backtrace backtraced backtraces backwardtrace backwardtraces backwardtraced backwardtrack	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/25 11:48
-	30	backtracks backtracking backtracked ((back backward) near (trace traces traced tracing drive track tracks tracking tracked))) (simulation simulator) with ((fault faults) near (injection inject injecting injects injected))	USPAT; US-PGPUB;	2003/12/25 11:55
			EPO; JPO; DERWENT; IBM_TDB	
	2	(simulation simulator) with ((fault faults defect defects) near (injection inject injecting injects injected)) and (node nodes) and ((test adj vector) pattern) and (backtracing backtrace backtraced backtraces backwardtrace backwardtraces backwardtraced ((back backward) near (trace traces traced tracing drive)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/25 10:44
-	44	((logic circuit logical (fault adj free) (good adj machine)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects) and (node nodes) and ((test adj vector) pattern) and scan	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/25 11:44
-	46	(((logic circuit logical (fault adj free)) adj (simulation simulator)) (good adj machine)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects) and (node nodes) and ((test adj vector) pattern) and scan	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/25 11:55
-	16	(((logic circuit logical (fault adj free)) adj (simulation simulator)) (good adj machine)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects) and (node nodes) and ((test adj vector) pattern) and ((partial full) adj scan)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/25 11:46
-	4	((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects) and (node nodes) and ((test adj vector) pattern) and (backtracing backtrace backtraced backtraces backwardtrace backwardtraces backwardtraced backwardtracing backtrack backtracks backtracking backtracked ((back backward) near (trace traces traced tracing drive track tracks tracking tracked))) and ((partial full)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/26 07:12
-	7	adj scan) (((logic circuit logical (fault adj free)) adj (simulation simulator)) (good adj machine)) and ((fault defect) adj (simulation simulator)) and (backtracing backtrace backtraced backtraces backwardtrace backwardtraces backwardtraced backwardtracing backtrack backtracks backtracking backtracked ((back backward) near (trace traces traced tracing drive track tracks tracking tracked))) and ((partial full) adj scan)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/26 07:11

-	1	(true adj value adj (simulati n simulator)) and ((fault defect) adj (simulation simulator)) and (backtracing backtrace backtraced backtraces backwardtrace backwardtraces backwardtraced backwardtracing backtrack backtracks backtracking backtracked ((back backward) near (trace traces	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/26 07:12
-	3	traced tracing drive track tracks tracking tracked))) and ((partial full) adj scan) (simulation simulator) with ((fault faults) near (injection inject injecting injects injected)) and (backtracing backtrace backtraced backtraces backwardtraced backwardtraced backwardtraced backwardtraced backwardtraced	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/12/26 07:12
		backtracked ((back backward) near (trace traces traced tracing drive track tracks tracking tracked))) and ((partial full) adj scan)	1311_133	